

Stanislav Jurecka

List of Publications by Year in descending order

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Version: 2024-02-01

30
papers

292
citations

1163117

8
h-index

888059

17
g-index

31
all docs

31
docs citations

31
times ranked

183
citing authors

#	ARTICLE	IF	CITATIONS
1	Minkowski functional characterization and fractal analysis of surfaces of titanium nitride films. <i>Materials Research Express</i> , 2019, 6, 086463.	1.6	126
2	Multifractal and optical bandgap characterization of Ta ₂ O ₅ thin films deposited by electron gun method. <i>Optical and Quantum Electronics</i> , 2020, 52, 1.	3.3	46
3	Effect of annealing on the micromorphology and corrosion properties of Ti/SS thin films. <i>Superlattices and Microstructures</i> , 2020, 146, 106681.	3.1	29
4	Multifractal analysis of textured silicon surfaces. <i>Applied Surface Science</i> , 2014, 301, 46-50.	6.1	18
5	On the influence of the surface roughness onto the ultrathin SiO ₂ /Si structure properties. <i>Applied Surface Science</i> , 2010, 256, 5623-5628.	6.1	12
6	Multifractal analysis and optical properties of nanostructured silicon layers. <i>Applied Surface Science</i> , 2017, 395, 150-156.	6.1	12
7	Prepared γ -MnO ₂ thin films by chemical bath deposition methods and study of its optical and microstructure properties. <i>Optical and Quantum Electronics</i> , 2019, 51, 1.	3.3	10
8	Passivation of Si-based structures in HCN and KCN solutions. <i>Applied Surface Science</i> , 2012, 258, 8397-8405.	6.1	9
9	Study of density of interface states in MOS structure with ultrathin NAOS oxide. <i>Open Physics</i> , 2012, 10, .	1.7	4
10	On Topographic Properties of Semiconductor Surfaces and Thin Film Systems. <i>Materials Science Forum</i> , 2009, 609, 275-279.	0.3	3
11	Properties of charge states in MOS structure with ultrathin oxide layer. <i>Applied Surface Science</i> , 2012, 258, 8409-8414.	6.1	3
12	Measuring capacitance of various types of structures. , 2014, , .		3
13	On determination of properties of ultrathin and very thin silicon oxide layers by FTIR and X - ray reflectivity. <i>Materials Research Society Symposia Proceedings</i> , 2008, 1066, 1.	0.1	2
14	Structural Characterization of Iron in Human Spleen. <i>Materials Research Society Symposia Proceedings</i> , 2008, 1132, 1.	0.1	2
15	<title>Investigation of electrical, structural, and optical properties of very thin oxide/a-Si:H/c-Si interfaces passivated by cyanide treatment</title>. , 2004, 5774, 481.		1
16	On formation of thin SiO ₂ /a-Si:H interface when biased oxidized semiconductor surface interacts with plasma or liquid solution. <i>Open Physics</i> , 2007, 5, .	1.7	1
17	Study of microstructural and optical properties of a-Si:H thin films. , 2010, , .		1
18	Investigation of morphological and optical properties of nanostructured layers formed by the SSCT etching of silicon. <i>Applied Surface Science</i> , 2018, 461, 72-77.	6.1	1

#	ARTICLE	IF	CITATIONS
19	Microstructure and optical properties of layers formed by anodic etching of silicon. AIP Conference Proceedings, 2019, , .	0.4	1
20	Determination of thickness of electrochemically etched Si layers passivated by Si ₃ N ₄ by analysis of the experimental spectral reflectance. AIP Conference Proceedings, 2019, , .	0.4	1
21	Thickness and tensile stress determination of black silicon layers by spectral reflectance and Raman scattering. Journal of Electrical Engineering, 2019, 70, 51-57.	0.7	1
22	The cavity resonator design: stochastic optimization of the transmission line method. Proceedings of SPIE, 2011, , .	0.8	0
23	Analysis of linear and nonlinear effects in optical fiber. , 2016, , .		0
24	Properties of nanocrystalline Si layers embedded in structure of solar cell. Journal of Electrical Engineering, 2017, 68, 48-52.	0.7	0
25	Properties of nanostructured layers formed on silicon. AIP Conference Proceedings, 2018, , .	0.4	0
26	Reflectance analysis of porosity gradient in nanostructured silicon layers. , 2017, , .		0
27	Microstructure and optical properties of black silicon layers. , 2018, , .		0
28	Black silicon " correlation between microstructure and Raman scattering. Journal of Electrical Engineering, 2019, 70, 58-64.	0.7	0
29	Statistical and Fractal Analysis of Random Height Function. Communications - Scientific Letters of the University of Zilina, 2017, 19, 57-61.	0.6	0
30	Microstructure and optical properties of etched silicon layers for photovoltaic applications. , 2022, , .		0